



TA Technology (Shanghai) Co., Ltd.

**Test Lab Attestation Letter**

<b>Date of Test:</b>	From Sept. 01, 2013 to Sept 03., 2013
<b>Applicant Name:</b>	Quantun Electronics, LLC
<b>FCC ID:</b>	XMHQP-990-U1
<b>IC:</b>	8502A-QP990U1

<b>Tested By:</b>	Zhang Yi
<b>Title:</b>	SAR Engineer
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<b>Phone No.:</b>	+86-21-50791141

**Statement of Compliance:** TA Technology (Shanghai) Co., Ltd. declares that this Unit has been tested in accordance with the test method identified in this test report and that we observed it being tested. It also declares that the Unit complies with the relevant limits. All instrumentation and accessories used to test this unit for compliance to the indicated test method are calibrated regularly in accordance with ISO 17025:2005 requirements by laboratories accredited by A2LA, NVLAP, or ACLAS for the measurement parameters.

**The measurements were made at:** TA Technology (Shanghai) Co., Ltd.  
No.145, Jintang Rd, Tangzhen Industry Park, Pudong Shanghai, China

**Test Lab Witness-**

<b>Approved By:</b>	Yang Weizhong
<b>Title of Witness:</b>	Director
<b>Email Address:</b>	yangweizhong@ta-shanghai.com
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